

<b>Notice of References Cited</b>	Application/Control No. 10/024,432	Applicant(s)/Patent Under Reexamination KARGMAN ET AL.	
	Examiner Satish S. Rampuria	Art Unit 2124	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,848,415 A	12-1998	Guck, Randal Lee	707/10
*	B	US-2001/0039578 A1	11-2001	Tokumaru et al.	709/223
*	C	US-2004/0015911 A1	01-2004	Hinsley et al.	717/147
*	D	US-2003/0135845 A1	07-2003	Nunomura, Yasuhiro	717/136
*	E	US-2003/0035004 A1	02-2003	Dove et al.	345/762
*	F	US-2003/0101438 A1	05-2003	Mishra et al.	717/136
*	G	US-2003/0051073 A1	03-2003	Mishra et al.	709/332
*	H	US-6,341,372 B1	01-2002	Datig, William E.	717/136
*	I	US-6,083,279 A	07-2000	Cuomo et al.	717/118
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2001306387 A	11-2001	Japan	KUWAJIMA, TAKAO	G06F 12/00
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.